
Preskusne metode za električne materiale, tiskane plošče, povezovalne strukture in sestave – 5. del: Preskusne metode za sestave tiskanih plošč (IEC 61189-5:2006)

Test methods for electrical materials, interconnection structures and assemblies - Part 5: Test methods for printed board assemblies (IEC 61189-5:2006)

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**Test methods for electrical materials, interconnection structures
and assemblies**

**Part 5: Test methods for printed board assemblies
(IEC 61189-5:2006)**

Méthodes d'essais pour les matériaux
électriques, les structures
d'interconnexion et les ensembles
Partie 5: Méthodes d'essais
pour les cartes imprimées équipées
(CEI 61189-5:2006)

Prüfverfahren für Elektromaterialien,
Verbindungsstrukturen
und Baugruppen
Teil 5: Prüfverfahren
für bestückte Leiterplatten
(IEC 61189-5:2006)

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This European Standard was approved by CENELEC on 2006-09-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Cyprus, the Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland and the United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 91/564/FDIS, future edition 1 of IEC 61189-5, prepared by IEC TC 91, Electronics assembly technology, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61189-5 on 2006-09-01.

This standard forms part of a series and should be used in conjunction with other parts in the same series, under the main title *Test methods for electrical materials, interconnection structures and assemblies*:

Part 1: General test methods and methodology

Part 2: Test methods for materials for interconnection structures

Part 3: Test methods for interconnection structures (printed boards)

Part 4: Test methods for electronic components assembling characteristics

Part 5: Test methods for printed board assemblies

Part 6: Test methods for materials used in electronic assemblies

It should also be read in conjunction with EN 60068, Environmental testing.

The following dates were fixed:

- latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2007-06-01
- latest date by which the national standards conflicting with the EN have to be withdrawn (dow) 2009-09-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 61189-5:2006 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	1988	Environmental testing Part 1: General and guidance	EN 60068-1 ¹⁾	1994
IEC 60068-2-20	- ²⁾	Environmental testing Part 2: Tests - Test T: Soldering	HD 323.2.20 S3	1988 ³⁾
IEC 61189-1	- ²⁾	Test methods for electrical materials, printed boards and other interconnection structures and assemblies Part 1: General test methods and methodology	EN 61189-1	1997 ³⁾
IEC 61189-3	- ²⁾	Test methods for electrical materials, printed boards and other interconnection structures and assemblies Part 3: Test methods for interconnection structures (printed boards)	EN 61189-3	1997 ³⁾
IEC 61189-6	- ²⁾	Test methods for electrical materials, interconnection structures and assemblies Part 6: Test methods for materials used in manufacturing electronic assemblies	EN 61189-6	2006 ³⁾
IEC 61190-1-1	- ²⁾	Attachment materials for electronic assembly Part 1-1: Requirements for soldering fluxes for high-quality interconnections in electronics assembly	EN 61190-1-1	2002 ³⁾
IEC 61190-1-2	2002	Attachment materials for electronic assembly Part 1-2: Requirements for solder pastes for high-quality interconnections in electronics assembly	EN 61190-1-2	2002
IEC 61190-1-3	- ²⁾	Attachment materials for electronic assembly Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solders for electronic soldering applications	EN 61190-1-3	2002 ³⁾

¹⁾ EN 60068-1 includes corrigendum October 1988 + A1:1992 to IEC 60068-1.

²⁾ Undated reference.

³⁾ Valid edition at date of issue.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61249-2-7	- ²⁾	Materials for printed boards and other interconnecting structures Part 2-7: Reinforced base materials, clad and unclad - Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad	EN 61249-2-7 + corr. September	2002 ³⁾ 2005
IEC 62137 + corr. January	2004 2005	Environmental and endurance testing - Test methods for surface-mount boards of area array type packages FBGA, BGA, FLGA, LGA, SON and QFN	EN 62137 + corr. February	2004 2005
ISO 5725-2	- ²⁾	Accuracy (trueness and precision) of measurement methods and results Part 2: Basic method for the determination of repeatability and reproducibility of a standard measurement method	-	-
ISO 9001	- ²⁾	Quality management systems - Requirements	EN ISO 9001	2000 ³⁾
ISO 9455-1	- ²⁾	Soft soldering fluxes - Test methods Part 1: Determination of non-volatile matter, gravimetric method	EN 29455-1	1993 ³⁾
ISO 9455-2	- ²⁾	Soft soldering fluxes - Test methods Part 2: Determination of non-volatile matter, ebulliometric method	EN ISO 9455-2	1995 ³⁾

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INTERNATIONAL STANDARD

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**Test methods for electrical materials,
interconnection structures and assemblies –**

**Part 5:
Test methods for printed board assemblies**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**TEST METHODS FOR ELECTRICAL MATERIALS,
INTERCONNECTION STRUCTURES AND ASSEMBLIES –**

Part 5: Test methods for printed board assemblies

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61189-5 has been prepared by IEC technical committee 91: Electronic assembly technology.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/608/FDIS	91/619/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This standard is to be used in conjunction with the following parts of IEC 61189:

Part 1: General test methods and methodology

Part 2: Test methods for materials for interconnection structures

Part 3: Test methods for interconnection structures (printed boards)

Part 4: Test methods for electronic components assembling characteristics

Part 6: Test methods for materials used in electronic assemblies

and also the following standard:

IEC 60068: Environmental testing

The list of all the parts of the IEC 61189 series, under the general title *Test methods for electrical materials, interconnection structures and assemblies*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC website under <http://webstore.iec.ch> in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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INTRODUCTION

IEC 61189 relates to test methods for printed boards and printed board assemblies, as well as related materials or component robustness, irrespective of their method of manufacture.

The standard is divided into separate parts, covering information for the designer and the test methodology engineer or technician. Each part has a specific focus; methods are grouped according to their application and numbered sequentially as they are developed and released.

In some instances test methods developed by other TCs (for example, TC 104) have been reproduced from existing IEC standards in order to provide the reader with a comprehensive set of test methods. When this situation occurs, it will be noted on the specific test method; if the test method is reproduced with minor revision, those paragraphs that are different are identified.

This part of IEC 61189 contains test methods for evaluating printed board assemblies. The methods are self-contained, with sufficient detail and description so as to achieve uniformity and reproducibility in the procedures and test methodologies.

The tests shown in this standard are grouped according to the following principles:

P: preparation/conditioning methods

V: visual test methods

D: dimensional test methods

C: chemical test methods

M: mechanical test methods

E: electrical test methods

N: environmental test methods

X: miscellaneous test methods

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To facilitate reference to the tests, to retain consistency of presentation, and to provide for future expansion, each test is identified by a number (assigned sequentially) added to the prefix (group code) letter showing the group to which the test method belongs.

The test method numbers have no significance with respect to an eventual test sequence; that responsibility rests with the relevant specification that calls for the method being performed. The relevant specification, in most instances, also describes pass/fail criterion.

The letter and number combinations are for reference purposes to be used by the relevant specification. Thus "5C01" represents the first chemical test method described in IEC 61189-5.

In short, in this example, 5 is the number of the part of IEC 61189, C is the group of methods, and 01 is the test number.

A list of all test methods included in this standard, as well as those under consideration, is given in Annex B. This annex will be reissued whenever new tests are introduced.

TEST METHODS FOR ELECTRICAL MATERIALS, INTERCONNECTION STRUCTURES AND ASSEMBLIES –

Part 5: Test methods for printed board assemblies

1 Scope

This part of IEC 61189 is a catalogue of test methods representing methodologies and procedures that can be applied to test printed board assemblies.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-20, *Environmental testing – Part 2-20: Tests – Test T: Soldering*

IEC 61189-1, *Test methods for electrical materials, interconnection structures and assemblies – Part 1: General test methods and methodology*

IEC 61189-3, *Test methods for electrical materials, interconnection structures and assemblies – Part 3: Test methods for interconnection structures (printed boards)*

IEC 61189-6, *Test methods for electrical materials, interconnection structures and assemblies – Part 6: Test methods for materials used in manufacturing electronic assemblies*

IEC 61190-1-1, *Attachment materials for electronic assembly – Part 1-1: Requirements for soldering fluxes for high-quality interconnections in electronics assembly*

IEC 61190-1-2:2002, *Attachment materials for electronic assembly – Part 1-2: Requirements for solder pastes for high-quality interconnections in electronics assembly*

IEC 61190-1-3, *Attachment materials for electronic assembly – Part 1-3: Requirements for electronic grade solder alloys and fluxed and non-fluxed solid solders for electronic soldering applications*

IEC 61249-2-7, *Materials for printed boards and other interconnecting structures – Part 2-7: Reinforced base materials clad and unclad – Epoxide woven E-glass laminated sheet of defined flammability (vertical burning test), copper-clad*

IEC 62137:2004, *Environmental and endurance testing - Test methods for surface-mount boards of area array type packages FBGA, BGA, FLGA, LGA, SON and QFN*

ISO 5725-2, *Accuracy (trueness and precision) of measurement methods and results – Part 2: Basic method for the determination of repeatability and reproducibility of a standard measurement method*

ISO 9001, *Quality management systems – Requirements*

ISO 9455-1, *Soft soldering fluxes – Test methods – Part 1: Determination of non-volatile matter, gravimetric method*

ISO 9455-2, *Soft soldering fluxes – Test methods – Part 2: Determination of non-volatile matter, ebulliometric method*

3 Accuracy, precision and resolution

Errors and uncertainties are inherent in all measurement processes. The information given below enables valid estimates of the amount of error and uncertainty to be taken into account.

Test data serve a number of purposes which include

- monitoring of a process;
- enhancing of confidence in quality conformance;
- arbitration between customer and supplier.

In any of these circumstances, it is essential that confidence can be placed upon the test data in terms of

- accuracy: calibration of the test instruments and/or system;
- precision: the repeatability and uncertainty of the measurement;
- resolution: the suitability of the test instrument and/or system.

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3.1 Accuracy

The regime by which routine calibration of the test equipment is undertaken shall be clearly stated in the quality documentation of the supplier or agency conducting the test and shall meet the requirements of ISO 9001. <https://standards.iteh.ai/catalog/standards/sist/79a97e77-e23b-40cb-9e2f-d51b4442ad76/sist-en-61189-5-2006>

The calibration shall be conducted by an agency having accreditation to a national or international measurement standard institute. There should be an uninterrupted chain of calibration to a national or international standard.

Where calibration to a national or international standard is not possible, round-robin techniques may be used and documented to enhance confidence in measurement accuracy.

The calibration interval shall normally be one year. Equipment consistently found to be outside acceptable limits of accuracy shall be subject to shortened calibration intervals. Equipment consistently found to be well within acceptable limits may be subject to relaxed calibration intervals.

A record of the calibration and maintenance history shall be maintained for each instrument. These records should state the uncertainty of the calibration technique (in \pm % deviation) in order that uncertainties of measurement can be aggregated and determined.

A procedure shall be implemented to resolve any situation where an instrument is found to be outside calibration limits.

3.2 Precision

The uncertainty budget of any measurement technique is made up of both systematic and random uncertainties. All estimates shall be based upon a single confidence level, the minimum being 95 %.

Systematic uncertainties are usually the predominant contributor and will include all uncertainties not subject to random fluctuation. These include

- calibration uncertainties;
- errors due to the use of an instrument under conditions which differ from those under which it was calibrated;
- errors in the graduation of a scale of an analogue meter (scale shape error).

Random uncertainties result from numerous sources but can be deduced from repeated measurement of a standard item. Therefore, it is not necessary to isolate the individual contributions. These may include

- random fluctuations such as those due to the variation of an influence parameter. Typically, changes in atmospheric conditions reduce the repeatability of a measurement;
- uncertainty in discrimination, such as setting a pointer to a fiducial mark or interpolating between graduations on an analogue scale.

Aggregation of uncertainties: Geometric addition (root-sum-square) of uncertainties may be used in most cases. Interpolation error is normally added separately and may be accepted as being 20 % of the difference between the finest graduations of the scale of the instrument.

$$U_t = \pm \sqrt{(U_s^2 + U_r^2)} + U_i$$

where

U_t is the total uncertainty;

U_s is the systematic uncertainty;

U_r is the random uncertainty;

U_i is the interpolation error.

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Determination of random uncertainties: Random uncertainty can be determined by repeated measurement of a parameter and subsequent statistical manipulation of the measured data. The technique assumes that the data exhibits a normal (Gaussian) distribution.

$$U_r = \frac{t \times \sigma}{\sqrt{n}}$$

where

U_r is the random uncertainty;

n is the sample size;

t is the percentage point of the t distribution as shown in Table 1;

σ is the standard deviation (σ_{n-1}).

3.3 Resolution

It is paramount that the test equipment used is capable of sufficient resolution. Measurement systems used should be capable of resolving 10 % (or better) of the test limit tolerance.

It is accepted that some technologies will place a physical limitation upon resolution (for example, optical resolution).

3.4 Report

In addition to requirements detailed in the test specification, the report shall detail

- a) the test method used;
- b) the identity of the sample(s);
- c) the test instrumentation;
- d) the specified limit(s);